HAC TEST REPORT

Applicant	Sun Cupid Technology (HK) Ltd.
FCC ID	2ADINA6LC
Product	LTE Smart phone
Brand	NUU
Model	A6L-C, A6LC
Report No.	R1808A0402-H1V1
Issue Date	October 26, 2018

TA Technology (Shanghai) Co., Ltd. tested the above equipment in accordance with the requirements in **ANSI C63.19-2011.** The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Performed by: Jiangpeng Lan *Approved by: Kai Xu*

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1 Test Laboratory

1.1 Notes of the Test Report

This report shall not be reproduced in full or partial, without the written approval of **TA Technology (Shanghai) Co., Ltd.**The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein .Measurement Uncertainties were not taken into account and are published for informational purposes only. This report is written to support regulatory compliance of the applicable standards stated above.

1.2 Test facility

CNAS (accreditation number: L2264)

TA Technology (Shanghai) Co., Ltd. has obtained the accreditation of China National Accreditation Service for Conformity Assessment (CNAS).

FCC (Designation number: CN1179, Test Firm Registration Number: 446626)

TA Technology (Shanghai) Co., Ltd. has been listed on the US Federal Communications Commission list of test facilities recognized to perform electromagnetic emissions measurements.

IC (recognition number is 8510A)

TA Technology (Shanghai) Co., Ltd. has been listed by industry Canada to perform electromagnetic emission measurement.

VCCI (recognition number is C-4595, T-2154, R-4113, G-10766)

TA Technology (Shanghai) Co., Ltd. has been listed by industry Japan to perform electromagnetic emission measurement.

A2LA (Certificate Number: 3857.01)

TA Technology (Shanghai) Co., Ltd. has been listed by American Association for Laboratory Accreditation to perform electromagnetic emission measurement.

1.3 Testing Location

Company:	TA Technology (Shanghai) Co., Ltd.
Address:	No.145, Jintang Rd, Tangzhen Industry Park, Pudong Shanghai, China
City:	Shanghai
Post code:	201201
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E-mail:	xukai@ta-shanghai.com

1.4 Laboratory Environment

Temperature	Min. = 18°C, Max. = 28 °C
Relative humidity	Min. = 0%, Max. = 80%
Ground system resistance	< 0.5 Ω
Ambient noise is checked and found very low and in compliance with requirement of standards. Reflection of surrounding objects is minimized and in compliance with requirement of standards.	

2 Statement of Compliance

Table 2.1: The Total M-rating of each tested band

Mode	Rating
GSM 850	M4
GSM 1900	M3
CDMA BC0:	M4
CDMA BC1:	M4
CDMA BC10:	M4
WCDMA	M4
Date of Testing: August 30, 2018	
Note: Refer to section 7 Evaluation for Low-power Exemption. RF Emission testing for this device is required only for GSM/CDMA voice modes and LTE-TDD. All other applicable air-interfaces are exempt from testing in accordance with C93.19-2011 Clause 4.4 and are rated M4.	

3 Description of Equipment under Test

Client Information

Applicant	Sun Cupid Technology (HK) Ltd.
Applicant address	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Manufacturer	Sun Cupid Technology (HK) Ltd.
Manufacturer address	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.

General Technologies

Device Type:	Portable Device	
State of Sample:	Production Unit	
Model:	A6L-C, A6LC	
IMEI:	359696090007131	
Hardware Version:	S01	
Software Version:	A6LC-SP-15	
Antenna Type:	Internal Antenna	
Power Class:	GSM 850: 4 GSM 1900: 1 CDMA BC0/1/10:3 WCDMA Band II/IV/V: 3 LTE FDD 2/4/5/7/12/17/25/26: 3 LTE TDD 41: 3	
Power Level	GSM 850 level 5 GSM 1900: level 0 CDMA BC0/1/10: all up bits WCDMA Band II/IV/VIII: All up bits LTE FDD 2/4/5/7/12/17/25/26: max power LTE TDD 41: max power	
Test Modulation:	(GSM)GMSK; (WCDMA) QPSK; (CDMA) QPSK; (LTE) QPSK, 16QAM	
Operating Frequency Range(s):	**Mode**	**Tx (MHz)**
	GSM 850	824 ~ 849
	GSM 1900	1850 ~ 1910
	CDMA BC0:	824 ~ 849
	CDMA BC1:	1850 ~ 1910

	CDMA BC10:	817 ~ 824
	WCDMA Band II	1850 ~ 1910
	WCDMA Band IV	1710 ~ 1755
	WCDMA Band V	824 ~ 849
	LTE FDD 2	1850 ~ 1910
	LTE FDD 4	1710 ~ 1755
	LTE FDD 5	824 ~ 849
	LTE FDD 7	2500 ~ 2570
	LTE FDD 12	699 ~ 716
	LTE FDD 17	704 ~ 716
	LTE FDD 25	1850 ~ 1915
	LTE FDD 26	814 ~ 849
	LTE TDD 41	2496 ~ 2690
	Wi-Fi 2.4G	2412 ~ 2462
	BT	2402 ~ 2480
Accessory Equipment		
Adapter	Manufacturer: Shenzhen Ruide Electronic Industrial Co., Ltd. Model: RD0501000-USBA-18MG	
Battery	Manufacturer: Shenzhen Ruide Electronic Industrial Co.Ltd. Model: 455566ARV	
USB Cable	Manufacturer: Guangdong Wivtak Technology Co., LTD. Model: DA-B0118	

Air-Interface	Band (MHz)	Type	ANSI C63.19 tested	Simultaneous Transmissions	Name of Voice Service	Power Reduction
GSM	850	VO	Yes	Yes BT or Wi-Fi	NA	No
	1900					
	GPRS/EGPRS	DT	No			
CDMA	BC0	VO	Yes	Yes BT or Wi-Fi	NA	No
	BC1					
	BC10					
WCDMA	Band II	VO	No#	Yes BT or Wi-Fi	NA	No
	Band IV					
	Band V					
	HSPA	DT	No			
LTE	FDD 2	DT	No	Yes BT or Wi-Fi	NA	No
	FDD 4					
	FDD 5					
	FDD 7					
	FDD 12					
	FDD 17					
	FDD 25					
	FDD 26					
	TDD 41					
Wi-Fi	2450	DT	No	Yes GSM, CDMA, WCDMA, LTE	NA	No
Bluetooth (BT)	2450	DT	No	Yes GSM, CDMA, WCDMA, LTE	NA	No

VO= legacy Cellular Voice Service from Table 7.1 in 7.4.2.1 of ANSI C63.19-2011

DT= Digital Transport only (no voice)

Remark:

1. WCDMA is exempted from testing by low power exemption that its average antenna input power plus its MIF is ≤17 dBm,and is rated as M4.
2. This device has no VOIP function for LTE and WLAN.

4 Test Specification and Operational Conditions

4.1 Test Specification

The tests documented in this report were performed in accordance with the following:

FCC CFR47 Part 20.19
ANSI C63.19-2011
285076 D01 HAC Guidance v05
285076 D02 T-Coil Testing v03

5 Test Information

5.1 Operational Conditions during Test

5.1.1 General Description of Test Procedures

The phone was tested in all normal configurations for the ear use. The EUT is mounted in the device holder equivalent as for classic dosimeter measurements. The acoustic output of the EUT shall coincide with the center point of the area formed by the dielectric wire and the middle bar of the arch's top frame The EUT shall be moved vertically upwards until it touches the frame. The fine adjustment is possible by sliding the complete. The EUT holder is on the yellow base plate of the Test Arch phantom. These test configurations are tested at the high, middle and low frequency channels of each applicable operating mode.

A communication link is set up with a System Simulator (SS) by air link, and a call is established. The EUT is commanded to operate at maximum transmitting power.

5.2 HAC RF Measurements System Configuration

5.2.1 HAC Measurement Set-up

These measurements are performed using the DASY5 automated dosimetric assessment system. It is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland. It consists of high precision robotics system (Stäubli), robot controller, Intel Core2 computer, near-field probe, probe alignment sensor. The robot is a six-axis industrial robot performing precise movements. Cell controller systems contain the power supply, robot controller, teach pendant (Joystick) and remote control, and are used to drive the robot motors. The Stäubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit performs the signal amplification; signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

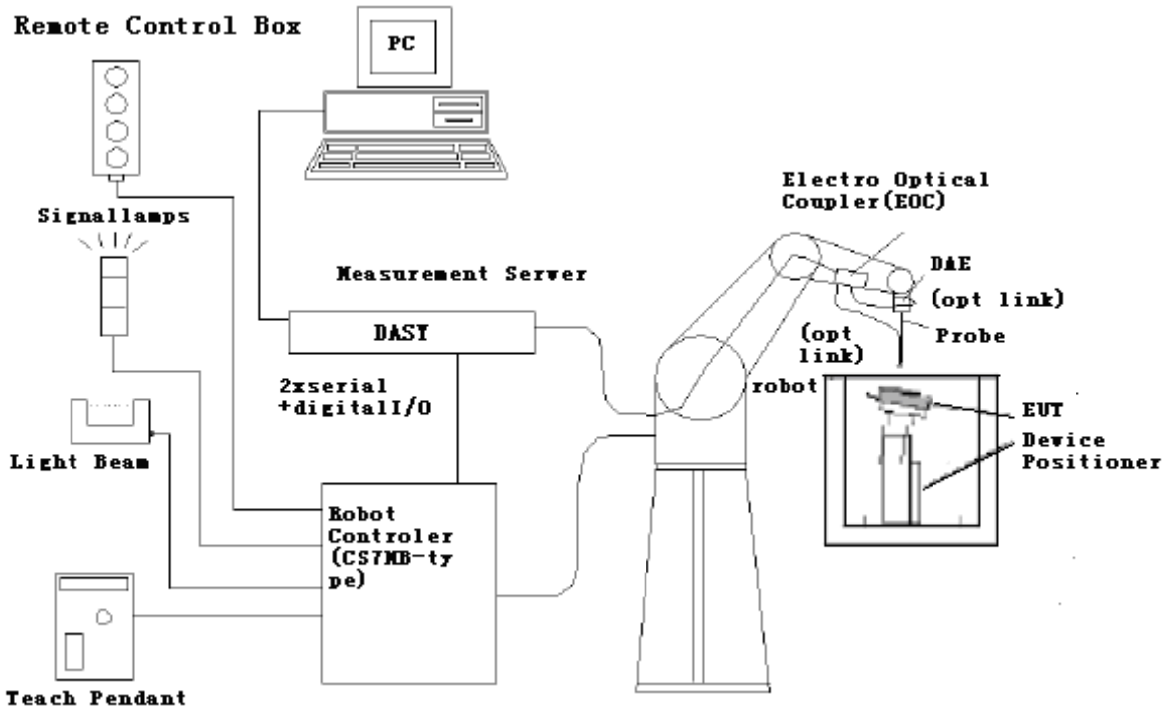


Figure 1 HAC Test Measurement Set-up

The DAE4 consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.

5.2.2 Probe System

The HAC measurements were conducted with the E-Field Probe EF3DV3 and the H-Field Probe H3DV6 (manufactured by SPEAG), designed in the classical triangular configuration and optimized for dosimetric evaluation.

E-Field Probe Description

Construction	One dipole parallel, two dipoles normal to probe axis Built-in shielding against static charges PEEK enclosure material
Calibration	In air from 100 MHz to 3.0 GHz (absolute accuracy ±6.0%, k=2)
Frequency	40 MHz to > 6 GHz (can be extended to < 20 MHz) Linearity: ± 0.2 dB (100 MHz to 3 GHz)
Directivity	± 0.2 dB in air (rotation around probe axis) ± 0.4 dB in air (rotation normal to probe axis)

Figure 2 EF3DV3 E-field Probe

Dynamic Range	2 V/m to > 1000 V/m; Linearity: ± 0.2 dB
Dimensions	Overall length: 330 mm (Tip: 16 mm) Tip diameter: 8 mm (Body: 12 mm) Distance from probe tip to dipole centers: 2.5 mm
Application	General near-field measurements up to 6 GHz Field component measurements Fast automatic scanning in phantoms

5.2.3 Test Arch Phantom & Phone Positioner

The Test Arch phantom should be positioned horizontally on a stable surface. Reference markings on the Phantom allow the complete setup of all predefined phantom positions and measurement grids by manually teaching three points in the robot. It enables easy and well defined positioning of the phone and validation dipoles as well as simple teaching of the robot (Dimensions: 370 x 370 x 370 mm).
The Device reference point is set for the EUT at 6.3 mm, the Grid reference point is on the upper surface at the origin of the coordinates, and the “user point \Height Check 0.5 mm” is 0.5mm above the center, allowing verication of the gap of 0.5mm while the probe is positioned there.

The Phone Positioner supports accurate and reliable positioning of any phone with effect on near field <±0.5 dB.

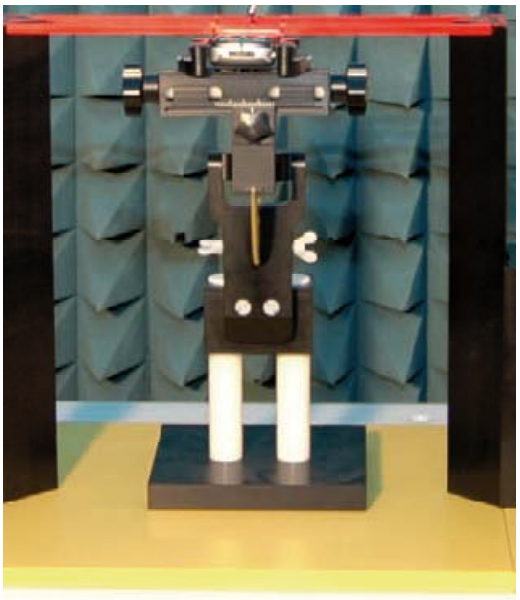


Figure 3 HAC Phantom & Device Holder

5.3 RF Test Procedures

The evaluation was performed with the following procedure:

1. Confirm proper operation of the field probe, probe measurement system and other instrumentation and the positioning system.
2. Position the WD in its intended test position. The gauge block can simplify this positioning. Note

that a separate E-field gauge block will be needed if the center of the probe sensor elements is at different distances from the tip of the probe.

3. Configure the WD normal operation for maximum rated RF output power, at the desired channel and other operating parameters (e.g., test mode), as intended for the test.
4. The center sub-grid shall center on the center of the axial measurement point or the acoustic output, as appropriate. Locate the field probe at the initial test position in the 50 mm by 50 mm grid, which is contained in the measurement plane. If the field alignment method is used, align the probe for maximum field reception.
5. Record the reading.
6. Scan the entire 50 mm by 50 mm region in equally spaced increments and record the reading at each measurement point. The grid is 5 cm by 5 cm area that is divided into 9 evenly sized blocks or sub-grids.The distance between measurement points shall be sufficient to assure the identification of the maximum reading.
7. Identify the five contiguous sub-grids around the center sub-grid with the lowest maximum field strength readings. Thus the six areas to be used to determine the WD's highest emissions are identified and outlined for the final manual scan. Please note that a maximum of five blocks can be excluded for both E-field measurements for the WD output being measured. Stated another way, the center sub-grid and three others must be common to both the E-field measurements.
8. Identify the maximum field reading within the non-excluded sub-grids identified in Step 7.
9. Convert the maximum field strength reading identified in Step 8 to V/m or A/m, as appropriate. For probes which require a probe modulation factor, this conversion shall be done using the appropriate probe modulation factor and the calibration.
10. Repeat Step 1 through Step 10 for both the E-field measurements.
11. Compare this reading to the categories in ANSI C63.19 Clause 8 and record the resulting category. The lowest category number listed in 8.2, Table 8.3 obtained in Step 10 for either E-field determines the M category for the audio coupling mode assessment. Record the WD category rating.

Figure 4 WD reference and plane for RF emission measurements

5.4 System Check

Validation Procedure

Place a dipole antenna meeting the requirements given in ANSI C63.19 D.11 in the position normally occupied by the WD. The dipole antenna serves as a known source for an electrical output. Position the E-field probe so that:

The probes and their cables are parallel to the coaxial feed of the dipole antenna.
The probe cables and the coaxial feed of the dipole antenna approach the measurement area from opposite directions.
Position the E-field probe at a 15 mm distance from the center of the probe element to the top surface.Validation was performed to verify that measured E-field is within +/-18% from the target refenence values provided by the manufacturer. ”Values within +/-18% are acceptable. Of which 12% is deviation and 13% is measurement uncertainty.”

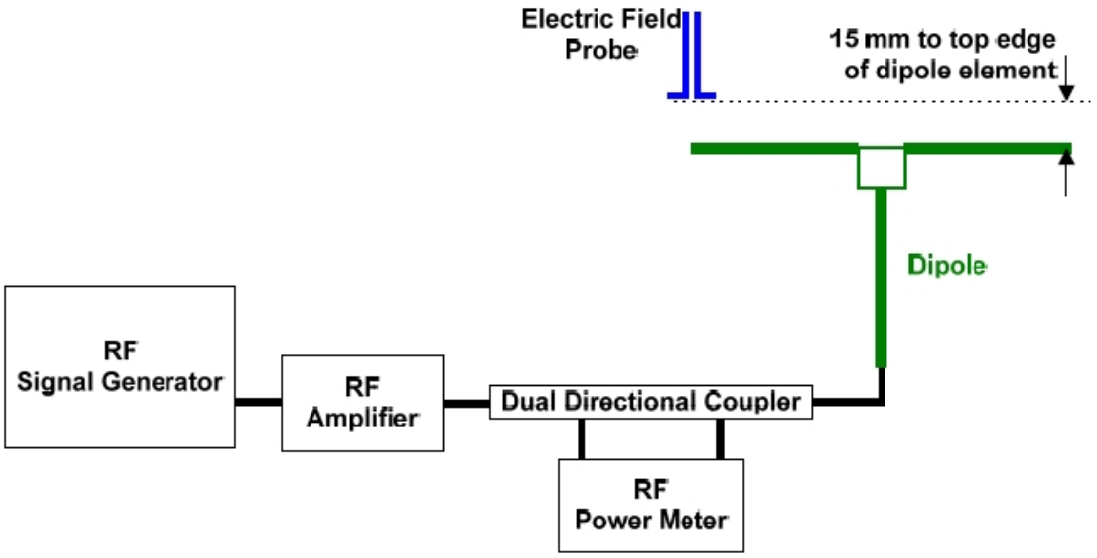


Figure 5 Dipole Validation Setup

Dipole Measurement Summary

Frequency (MHz)	Input Power (mW)	Target[1] Value (V/m)	Measured[2] Value (V/m)	Deviation[3] (%)	Test Date
835	100	106.6	107.3	-0.65	August 30, 2018
1880	100	90.5	92.1	-1.74	August 30, 2018

5.5 Average Antenna Input Power & Evaluation for Low-power Exemption

An RF air interface technology of a device is exempt from testing when its average antenna input power plus its **MIF is ≤17 dBm** for any of its operating modes. If a device supports multiple RF air interfaces, each RF air interface shall be evaluated individually.

Band	Average Antenna Input Power (dBm) (1)	Worst Case MIF (dB)	Input Power plus its MIF (dBm)	HAC Tested
GSM 850	33.0	3.63	36.63	Yes
GSM 1900	30.0	3.63	33.63	Yes
CDMA BC0	24.0	3.26	27.26	Yes
CDMA BC1	23.5	3.26	26.76	Yes
CDMA BC10	25.0	3.26	28.26	Yes
WCDMA B2	23.5	-27.23	-3.73	No
WCDMA B4	24.0	-27.23	-3.23	No
WCDMA B5	23.5	-27.23	-3.73	No

Note: 1. Max tune-up limit

2. MIF values applied in this test report were provided by the HAC equipment provider, SPEAG.

6 Test Results

6.1 ANSI C63.19-2011 Limits

Category	Telephone RF parameters < 960 MHz	Telephone RF parameters > 960 MHz
Near field	**E-field emissions**	
Category M1	50 to 55 dB (V/m)	40 to 45 dB (V/m)
Category M2	45 to 50 dB (V/m)	35 to 40 dB (V/m)
Category M3	40 to 45 dB (V/m)	30 to 35 dB (V/m)
Category M4	< 40 dB (V/m)	< 30 dB (V/m)

6.2 Summary Test Results

Band	Channel	Frequency (MHz)	MIF (dB)	E-Field Emissions dB (V/m)	Power Drift (dB)	Category	Graph Results
GSM 850	128	824.2	3.63	39.67	0.01	M4	1
	190	836.6	3.63	39.26	-0.01	M4	2
	251	848.8	3.63	39.65	0.00	M4	3
GSM 1900	512	1850.2	3.63	33.30	0.00	M3	4
	661	1880	3.63	33.36	0.08	M3	5
	810	1909.8	3.63	33.34	0.02	M3	6
CDMA BC0	1013	824.7	3.26	35.31	0.03	M4	7
	384	836.52	3.26	33.94	-0.04	M4	8
	777	848.31	3.26	35.25	0.08	M4	9
CDMA BC1	25	1851.25	3.26	16.42	-1.20	M4	10
	600	1880	3.26	17.21	-0.17	M4	11
	1175	1908.75	3.26	17.13	0.13	M4	12
CDMA BC10	450	817.25	3.26	35.13	0.07	M4	13
	560	820	3.26	37.83	-0.06	M4	14
	670	822.75	3.26	37.29	0.07	M4	15

7 Measurement Uncertainty

Measurement uncertainty evaluation template for DUT HAC RF test (ANSI C63.19-2011)

Error source	Type	Uncertainty Value (± %)	Prob. Dist.	k	c_i/E	c_i\H	Standard Uncertainty ui (± %) E	Degree of freedom Veff or vi
Measurement system								
Probe Calibration	B	5.1	N	1	1	1	5.1	∞
Axial Isotropy	B	4.7	R	1.732	1	1	2.7	∞
Sensor Displacement	B	16.5	R	1.732	1	0.145	9.5	∞
Boundary Effects	B	2.4	R	1.732	1	1	1.4	∞
Test Arch	B	7.2	R	1.732	1	0	4.2	∞
Linearity	B	4.7	R	1.732	1	1	2.7	∞
Scaling to Peak Envelope Power	B	2.0	R	1.732	1	1	1.2	∞
System Detection Limit	B	1.0	R	1.732	1	1	0.6	∞
Readout Electronics	B	0.3	N	1	1	1	0.3	∞
Response Time	B	0.8	R	1.732	1	1	0.5	∞
Integration Time	B	2.6	R	1.732	1	1	1.5	∞
RF Ambient Conditions	B	3.0	R	1.732	1	1	1.7	∞
RF Reflections	B	12.0	R	1.732	1	1	6.9	∞
Probe Positioner	B	1.2	R	1.732	1	0.67	0.7	∞
Probe Positioning	A	4.7	R	1.732	1	0.67	2.7	∞
Extra. And Interpolation	B	1.0	R	1.732	1	1	0.6	∞
Test sample related								
Device Positioning Vertical	B	4.7	R	1.732	1	0.67	2.7	∞
Device Positioning Lateral	B	1.0	R	1.732	1	1	0.6	∞
Device Holder and Phantom	B	2.4	R	1.732	1	1	1.4	∞
Power Drift	B	5.0	R	1.732	1	1	2.9	∞
Phantom and Setup related								
Phantom Thickness	B	2.4	R	1.732	1	0.67	1.4	∞
Combined standard uncertainty (%)							15.3	
Expanded Std. uncertainty on power (K=2)							30.6	
Expanded Std. uncertainty on field (K=2)							15.3	

8 Main Test Instruments

Name	Manufacturer	Type	Serial Number	Calibration Date	Expiration Time
Power meter	Agilent	E4417A	GB41291714	2018-05-20	2019-05-21
Power sensor	Agilent	N8481H	MY50350004	2018-05-20	2019-05-21
Signal Generator	Agilent	N5181A	MY50140143	2018-05-20	2019-05-21
Amplifier	INDEXSAR	IXA-020	0401	2018-05-20	2019-05-21
Universal Radio Communication Tester	R&S	CMU 200	118133	2018-05-20	2019-05-21
E-Field Probe	SPEAG	EF3DV3	4048	2018-01-09	2019-01-08
DAE	SPEAG	DAE4	1317	2018-03-23	2019-03-22
Validation Kit 835MHz	SPEAG	CD835V3	1133	2017-11-22	2018-11-20
Validation Kit 1880MHz	SPEAG	CD1880V3	1115	2017-11-22	2018-11-20
Hygrothermograph	Anymetr	NT-311	20150731	2018-05-22	2019-05-21
HAC Phantom	SPEAG	SD HAC P01 BB	1117	2017-11-22	2020-11-21
Software for Test	Speag	DASY5	52.8.8.1222	/	/
Software for Tissue	Agilent	85070	E06.01.36	/	/

*******END OF REPORT *******

ANNEX A: System Check Results

HAC_System Performance Check at 835MHz_E

DUT: Dipole 835 MHz; Type: CD835V3; SN:1023

Date: 8/30/2018

Communication System: CW; Frequency: 835 MHz;Duty Cycle: 1:1

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

E Scan - measurement distance from the probe sensor center to CD835 Dipole = 15mm

2/Hearing Aid Compatibility Test (41x361x1): Measurement grid: dx=5mm, dy=5mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 91 V/m; Power Drift = 0.003 dB

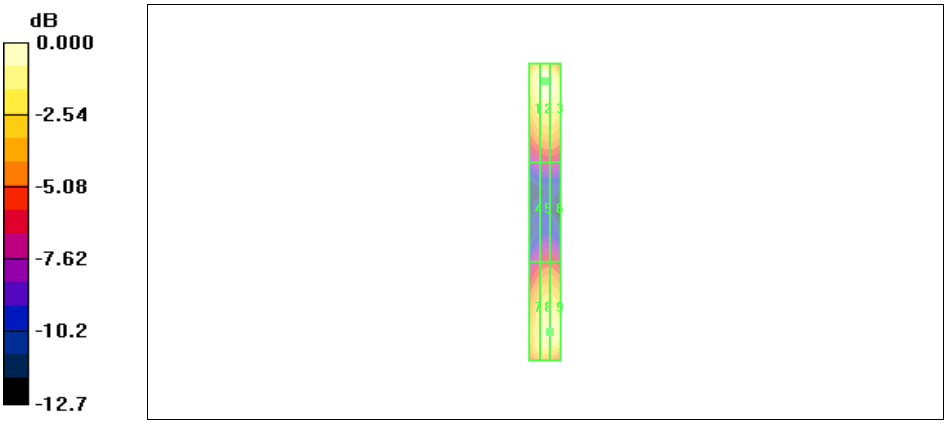
Applied MIF = 0.00 dB

Maximum value of peak Total field = 107.3 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

Peak E-field in V/m

Grid 1 **101.2 M4**	Grid 2 **104.3 M4**	Grid 3 **101.5 M4**
Grid 4 **61.2 M4**	Grid 5 **64.23 M4**	Grid 6 **62.39 M4**
Grid 7 **104.5 M4**	Grid 8 **107.3 M4**	Grid 9 **104.3 M4**



0 dB = 107.3V/m

HAC_System Performance Check at 1880MHz_E

DUT: Dipole 1880 MHz; Type: CD1880V3; SN: 1018

Date: 8/30/2018

Communication System: CW; Frequency: 1880 MHz;Duty Cycle: 1:1

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

E Scan - measurement distance from the probe sensor center to CD1880 Dipole = 15mm/Hearing Aid Compatibility Test (41x181x1): Measurement grid: dx=5mm, dy=5mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 86V/m; Power Drift = 0.002 dB

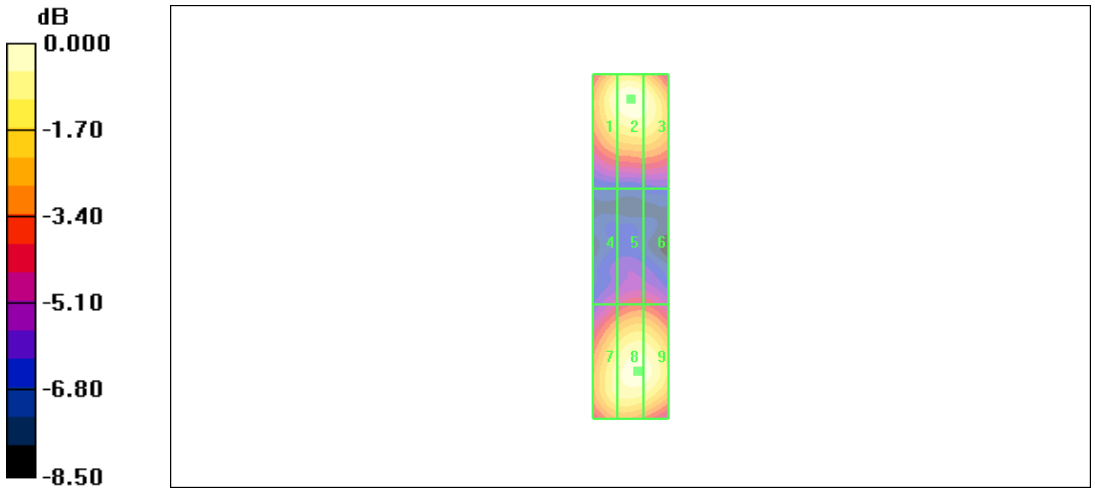
Applied MIF = 0.00 dB

Maximum value of peak Total field = 92.1 V/m

Hearing Aid Near-Field Category: M2 (AWF 0 dB)

Peak E-field in V/m

Grid 1 **91.78 M2**	Grid 2 **92.10 M2**	Grid 3 **91.42M2**
Grid 4 **71.76 M3**	Grid 5 **73.56 M3**	Grid 6 **71.17 M3**
Grid 7 **87.15 M2**	Grid 8 **89.46 M2**	Grid 9 **89.01 M2**



0 dB = 92.10V/m

ANNEX B: Graph Results

Plot 1 HAC RF E-Field GSM 850 Low

Date: 8/30/2018
Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 824.2 MHz;Duty Cycle: 1:8.6896
Phantom section: RF Section
DASY5 Configuration:
Sensor-Surface: 0mm (Fix Surface)
Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018
Electronics: DAE4 SN1317; Calibrated: 3/23/2018
Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM850 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device Low/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 84.17 V/m; Power Drift = 0.01 dB
Applied MIF = 3.63 dB
RF audio interference level = 39.67 dBV/m
Emission category: M4

MIF scaled E-field

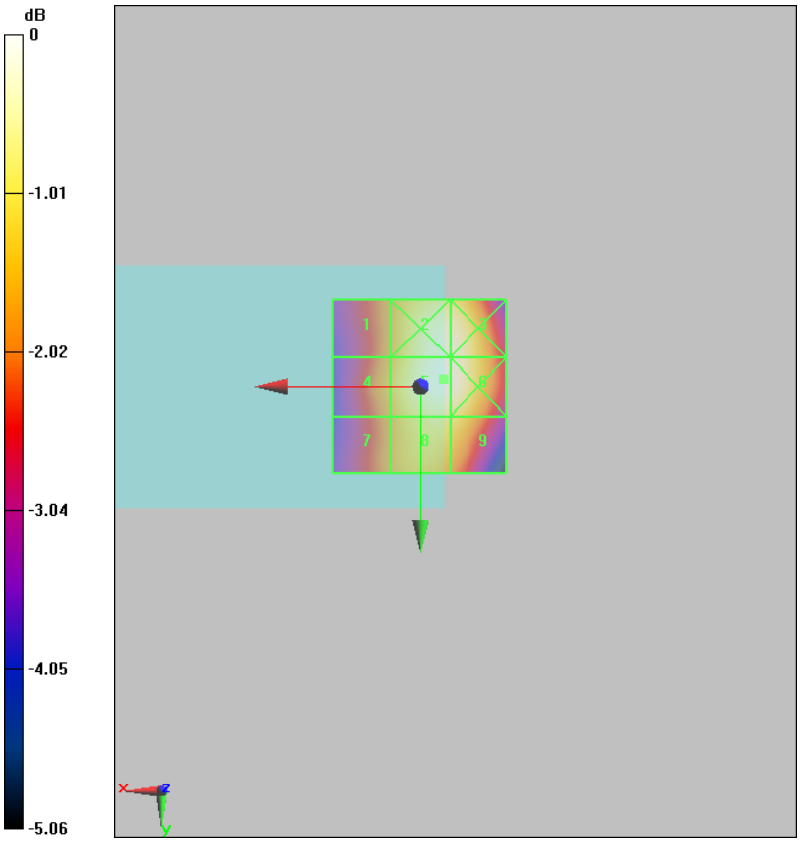
Grid 1 **M4** **38.02 dBV/m**	Grid 2 **M4** **39.56 dBV/m**	Grid 3 **M4** **39.56 dBV/m**
Grid 4 **M4** **38.26 dBV/m**	Grid 5 **M4** **39.67 dBV/m**	Grid 6 **M4** **39.63 dBV/m**
Grid 7 **M4** **37.97 dBV/m**	Grid 8 **M4** **39.02 dBV/m**	Grid 9 **M4** **38.96 dBV/m**

Cursor:

Total = 39.67 dBV/m

E Category: M4

Location: -6.5, -2, 7.7 mm



0 dB = 96.25 V/m = 39.67 dBV/m

Plot 2 HAC RF E-Field GSM 850 Middle

Date: 8/30/2018

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 836.6 MHz;Duty Cycle: 1:8.6896

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM850 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device Middle/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 83.64 V/m; Power Drift = -0.01 dB

Applied MIF = 3.63 dB

RF audio interference level = 39.26 dBV/m

Emission category: M4

MIF scaled E-field

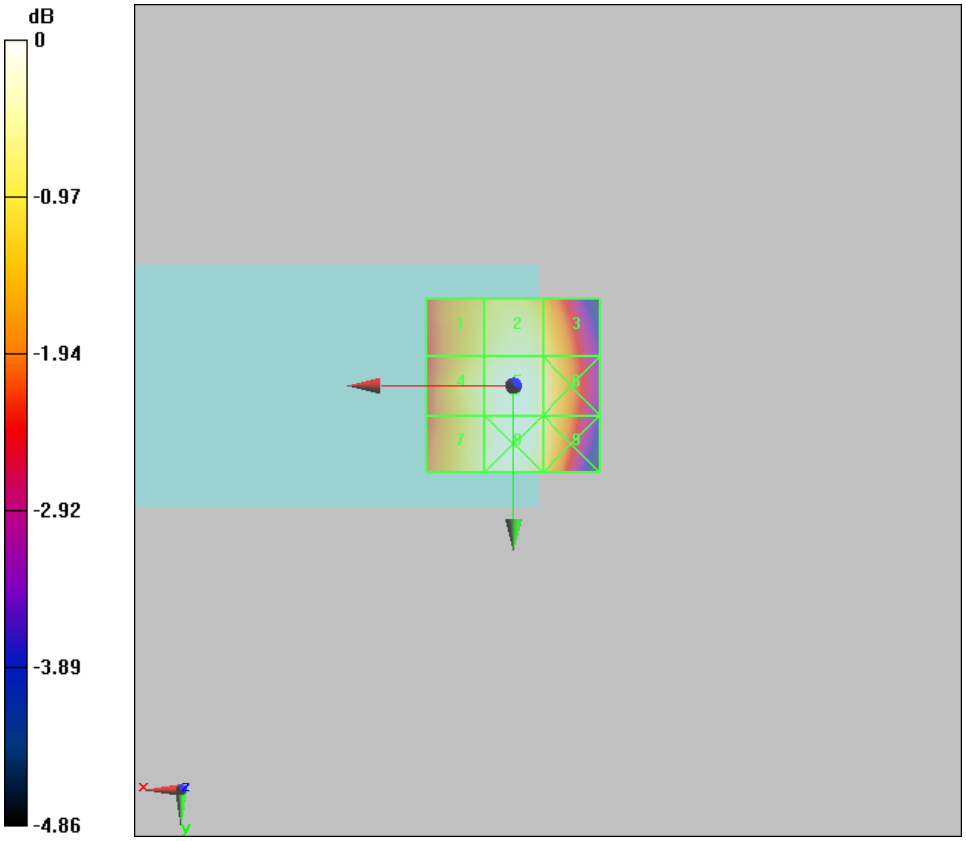
Grid 1 **M4** **38.47 dBV/m**	Grid 2 **M4** **38.95 dBV/m**	Grid 3 **M4** **38.64 dBV/m**
Grid 4 **M4** **38.84 dBV/m**	Grid 5 **M4** **39.26 dBV/m**	Grid 6 **M4** **38.87 dBV/m**
Grid 7 **M4** **38.82 dBV/m**	Grid 8 **M4** **39.24 dBV/m**	Grid 9 **M4** **38.83 dBV/m**

Cursor:

Total = 39.26 dBV/m

E Category: M4

Location: -0.5, 1.5, 7.7 mm



0 dB = 91.80 V/m = 39.26 dBV/m

Plot 3 HAC RF E-Field GSM 850 High

Date:8/30/2018

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 848.8 MHz;Duty Cycle: 1:8.6896

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM850 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device High/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 81.75 V/m; Power Drift = 0.00 dB

Applied MIF = 3.63 dB

RF audio interference level = 39.65 dBV/m

Emission category: M4

MIF scaled E-field

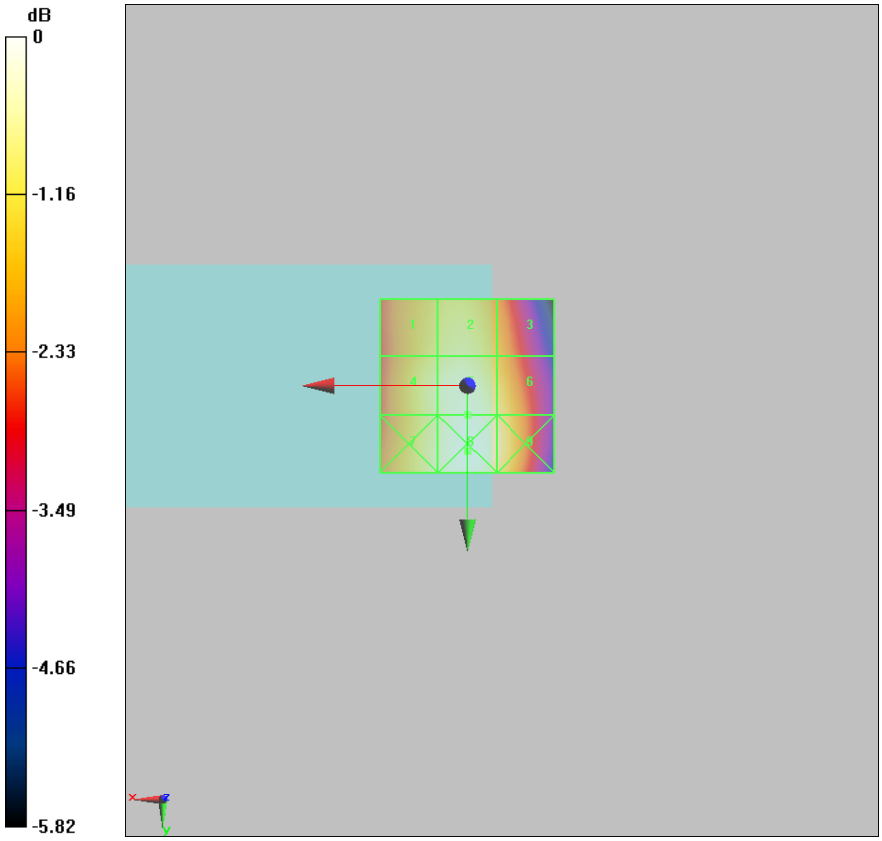
Grid 1 **M4** **38.84 dBV/m**	Grid 2 **M4** **39.11 dBV/m**	Grid 3 **M4** **38.31 dBV/m**
Grid 4 **M4** **39.26 dBV/m**	Grid 5 **M4** **39.65 dBV/m**	Grid 6 **M4** **39.11 dBV/m**
Grid 7 **M4** **39.32 dBV/m**	Grid 8 **M4** **39.82 dBV/m**	Grid 9 **M4** **39.3 dBV/m**

Cursor:

Total = 39.82 dBV/m

E Category: M4

Location: 0, 19, 7.7 mm



0 dB = 97.95 V/m = 39.82 dBV/m

Plot 4 HAC RF E-Field GSM 1900 Low

Date: 8/30/2018

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 1850.2 MHz;Duty Cycle: 1:8.6896

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM1900 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device Low/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 36.21 V/m; Power Drift = -0.00 dB

Applied MIF = 3.63 dB

RF audio interference level = 33.30 dBV/m

Emission category: M3

MIF scaled E-field

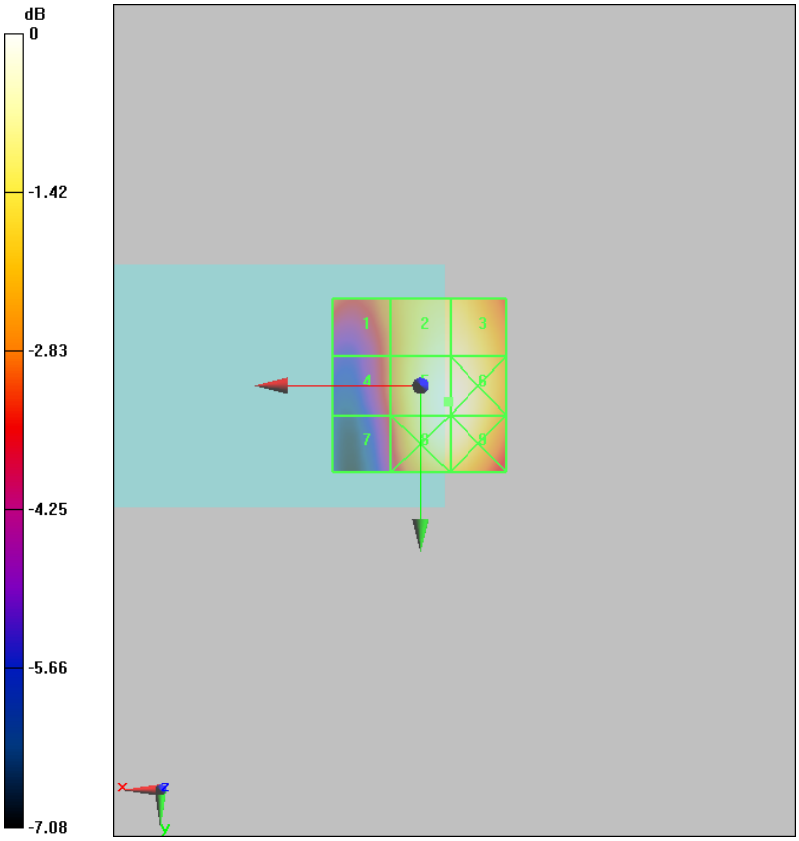
Grid 1 **M3** **30.99 dBV/m**	Grid 2 **M3** **32.87 dBV/m**	Grid 3 **M3** **32.86 dBV/m**
Grid 4 **M3** **30.56 dBV/m**	Grid 5 **M3** **33.3 dBV/m**	Grid 6 **M3** **33.3 dBV/m**
Grid 7 **M3** **30.04 dBV/m**	Grid 8 **M3** **33.26 dBV/m**	Grid 9 **M3** **33.23 dBV/m**

Cursor:

Total = 33.30 dBV/m

E Category: M3

Location: -8, 4.5, 7.7 mm



0 dB = 46.23 V/m = 33.30 dBV/m

Plot 5 HAC RF E-Field GSM 1900 Middle

Date: 8/30/2018

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 1880 MHz;Duty Cycle: 1:8.6896

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM1900 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device Middle/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 35.01 V/m; Power Drift = 0.08 dB

Applied MIF = 3.63 dB

RF audio interference level = 33.36 dBV/m

Emission category: M3

MIF scaled E-field

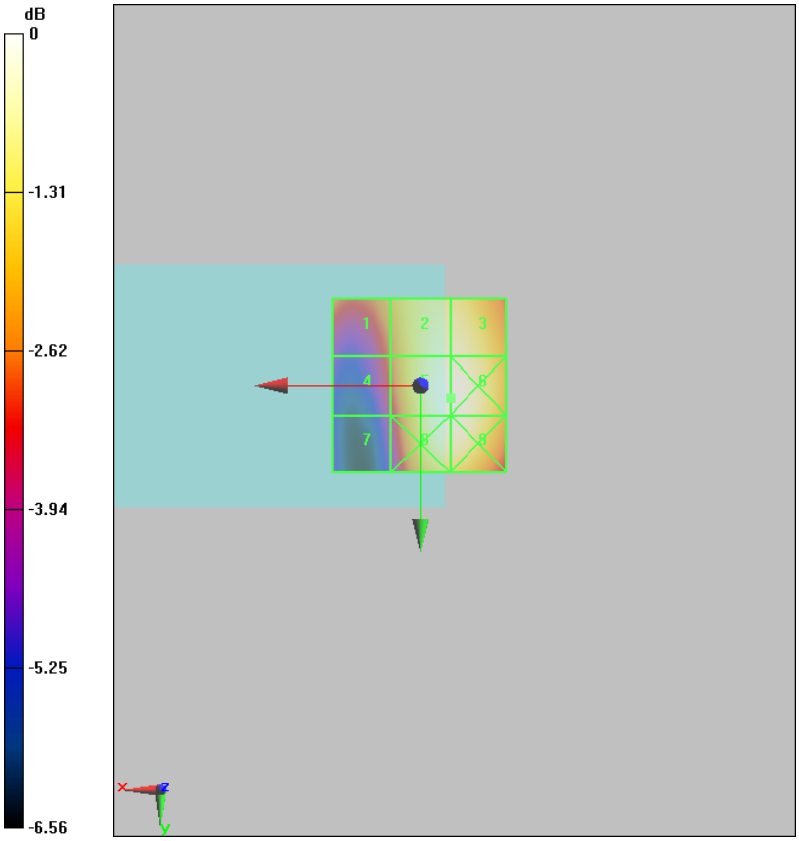
Grid 1 **M3** **31.37 dBV/m**	Grid 2 **M3** **33.04 dBV/m**	Grid 3 **M3** **33.04 dBV/m**
Grid 4 **M3** **30.6 dBV/m**	Grid 5 **M3** **33.36 dBV/m**	Grid 6 **M3** **33.36 dBV/m**
Grid 7 **M4** **29.63 dBV/m**	Grid 8 **M3** **33.32 dBV/m**	Grid 9 **M3** **33.32 dBV/m**

Cursor:

Total = 33.36 dBV/m

E Category: M3

Location: -8.5, 3.5, 7.7 mm



0 dB = 46.57 V/m = 33.36 dBV/m

Plot 6 HAC RF E-Field GSM 1900 High

Date: 8/30/2018

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 1909.8 MHz;Duty Cycle: 1:8.6896

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

GSM1900 HAC RF E-Field/E Scan - ER3D: 15 mm from Probe Center to the Device High/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 35.21 V/m; Power Drift = 0.02 dB

Applied MIF = 3.63 dB

RF audio interference level = 33.34 dBV/m

Emission category: M3

MIF scaled E-field

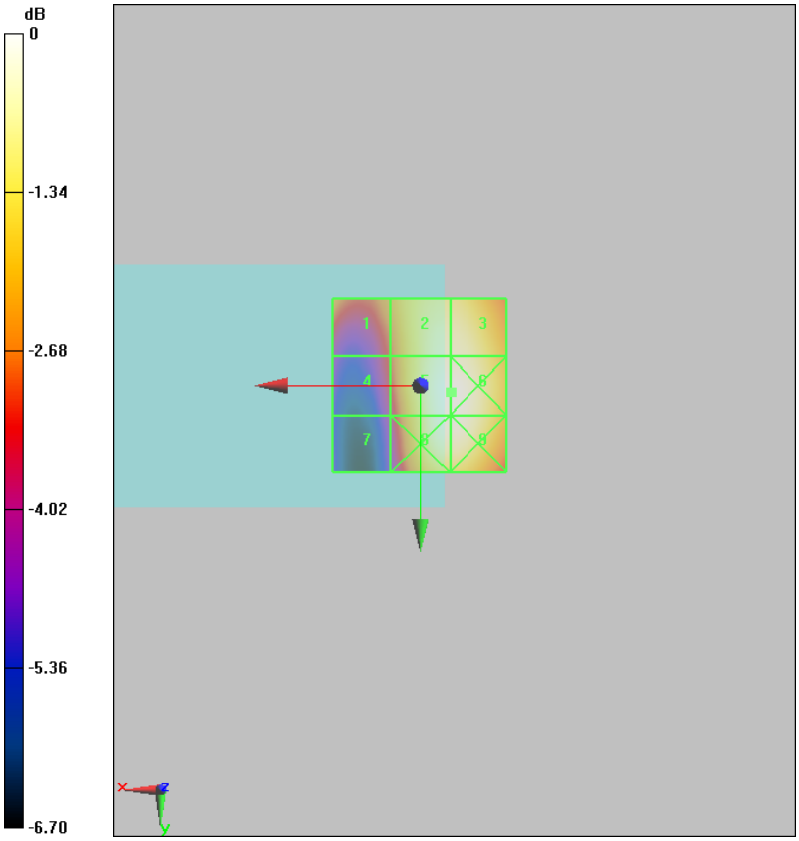
Grid 1 **M3** **31.22 dBV/m**	Grid 2 **M3** **33.02 dBV/m**	Grid 3 **M3** **33.02 dBV/m**
Grid 4 **M3** **30.33 dBV/m**	Grid 5 **M3** **33.34 dBV/m**	Grid 6 **M3** **33.34 dBV/m**
Grid 7 **M4** **29.47 dBV/m**	Grid 8 **M3** **33.27 dBV/m**	Grid 9 **M3** **33.27 dBV/m**

Cursor:

Total = 33.34 dBV/m

E Category: M3

Location: -9, 2, 7.7 mm



0 dB = 46.45 V/m = 33.34 dBV/m

Plot 7 HAC RF E-Field CDMA 0 Low

Date: 8/30/2018
Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 824.7 MHz;Duty Cycle: 1:17.7419
Phantom section: RF Section
DASY5 Configuration:
Sensor-Surface: 0mm (Fix Surface)
Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018
Electronics: DAE4 SN1317; Calibrated: 3/23/2018
Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC0 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Low/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 53.59 V/m; Power Drift = 0.03 dB
Applied MIF = 3.26 dB
RF audio interference level = 35.31 dBV/m
Emission category: M4

MIF scaled E-field

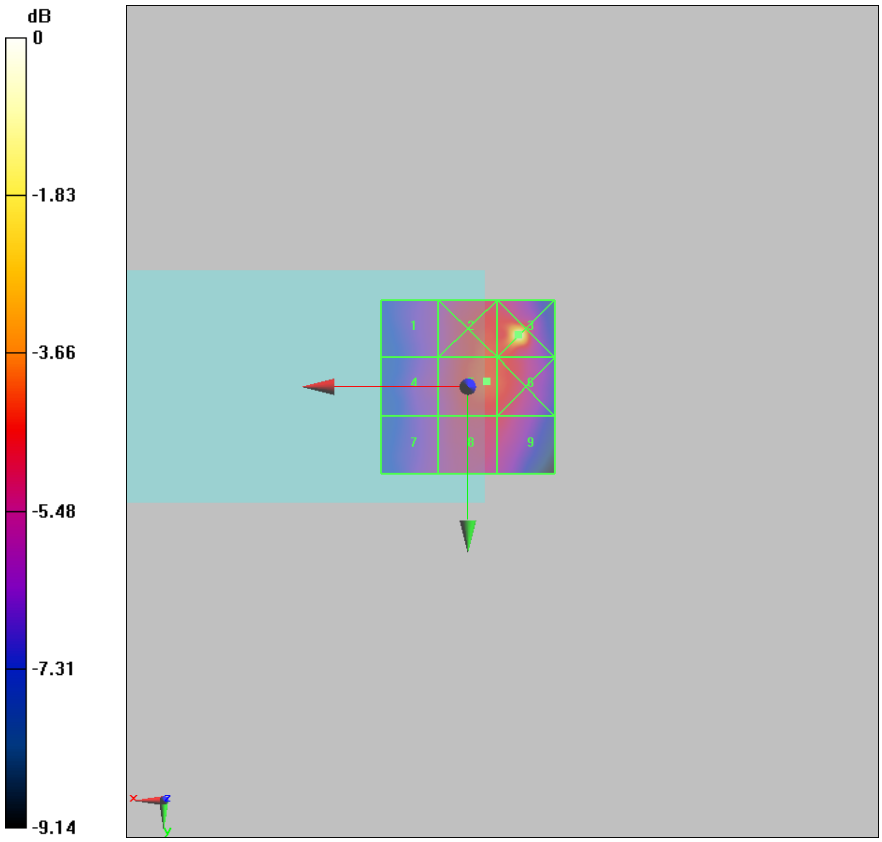
Grid 1 **M4** **33.76 dBV/m**	Grid 2 **M4** **35.26 dBV/m**	Grid 3 **M4** **39.44 dBV/m**
Grid 4 **M4** **34 dBV/m**	Grid 5 **M4** **35.31 dBV/m**	Grid 6 **M4** **35.22 dBV/m**
Grid 7 **M4** **33.78 dBV/m**	Grid 8 **M4** **34.62 dBV/m**	Grid 9 **M4** **34.62 dBV/m**

Cursor:

Total = 39.44 dBV/m

E Category: M4

Location: -14.5, -15, 7.7 mm



0 dB = 93.75 V/m = 39.44 dBV/m

Plot 8 HAC RF E-Field CDMA 0 Middle

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 836.52 MHz; Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC0 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Middle/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 47.40 V/m; Power Drift = -0.04 dB

Applied MIF = 3.26 dB

RF audio interference level = 33.94 dBV/m

Emission category: M4

MIF scaled E-field

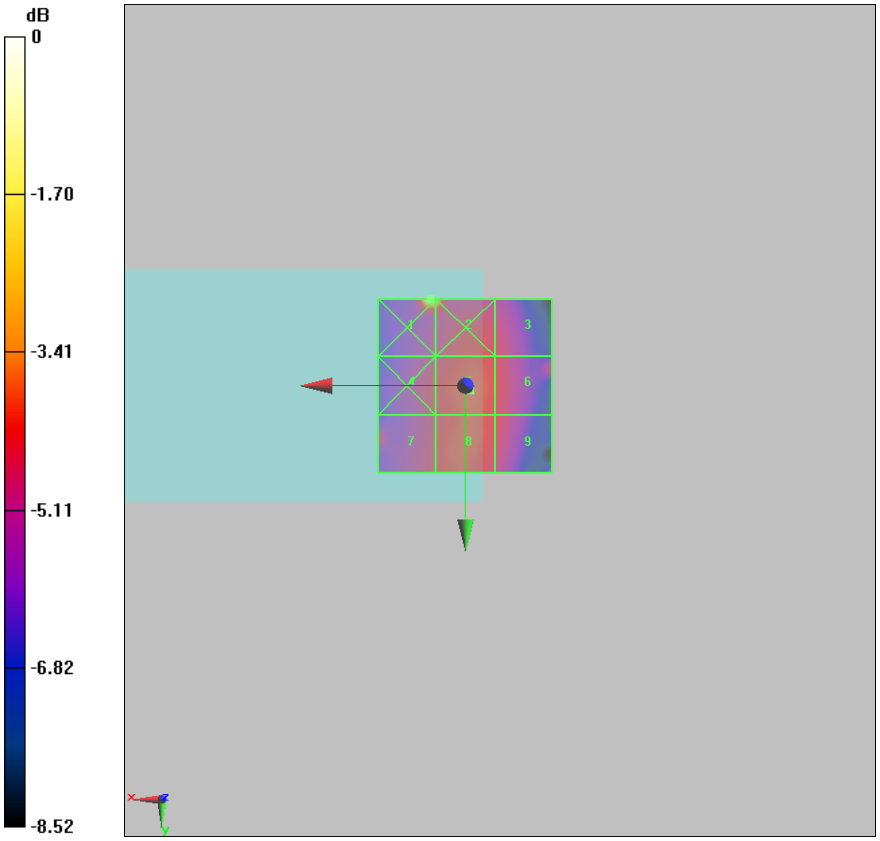
Grid 1 **M4** **37.87 dBV/m**	Grid 2 **M4** **36.86 dBV/m**	Grid 3 **M4** **33.4 dBV/m**
Grid 4 **M4** **33.48 dBV/m**	Grid 5 **M4** **33.94 dBV/m**	Grid 6 **M4** **33.6 dBV/m**
Grid 7 **M4** **33.53 dBV/m**	Grid 8 **M4** **33.9 dBV/m**	Grid 9 **M4** **33.51 dBV/m**

Cursor:

Total = 37.87 dBV/m

E Category: M4

Location: 10, -25, 7.7 mm



0 dB = 78.26 V/m = 37.87 dBV/m

Plot 9 HAC RF E-Field CDMA 0 High

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 848.31 MHz; Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC0 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device High/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 51.19 V/m; Power Drift = 0.08 dB

Applied MIF = 3.26 dB

RF audio interference level = 35.25 dBV/m

Emission category: M4

MIF scaled E-field

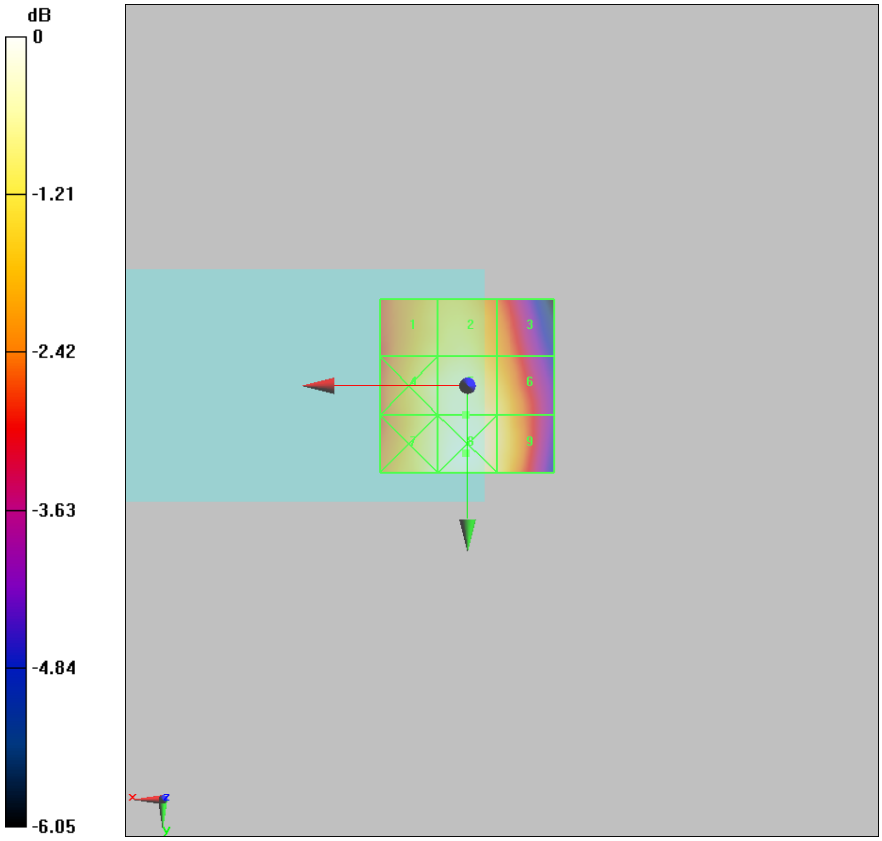
Grid 1 **M4** **34.41 dBV/m**	Grid 2 **M4** **34.65 dBV/m**	Grid 3 **M4** **33.76 dBV/m**
Grid 4 **M4** **34.87 dBV/m**	Grid 5 **M4** **35.25 dBV/m**	Grid 6 **M4** **34.7 dBV/m**
Grid 7 **M4** **35.03 dBV/m**	Grid 8 **M4** **35.48 dBV/m**	Grid 9 **M4** **34.85 dBV/m**

Cursor:

Total = 35.48 dBV/m

E Category: M4

Location: 0.5, 19.5, 7.7 mm



0 dB = 59.44 V/m = 35.48 dBV/m

Plot 10 HAC RF E-Field CDMA 1 Low

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 1851.25 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC1 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Low/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 11.18 V/m; Power Drift = -1.20 dB

Applied MIF = 3.26 dB

RF audio interference level = 16.42 dBV/m

Emission category: M4

MIF scaled E-field

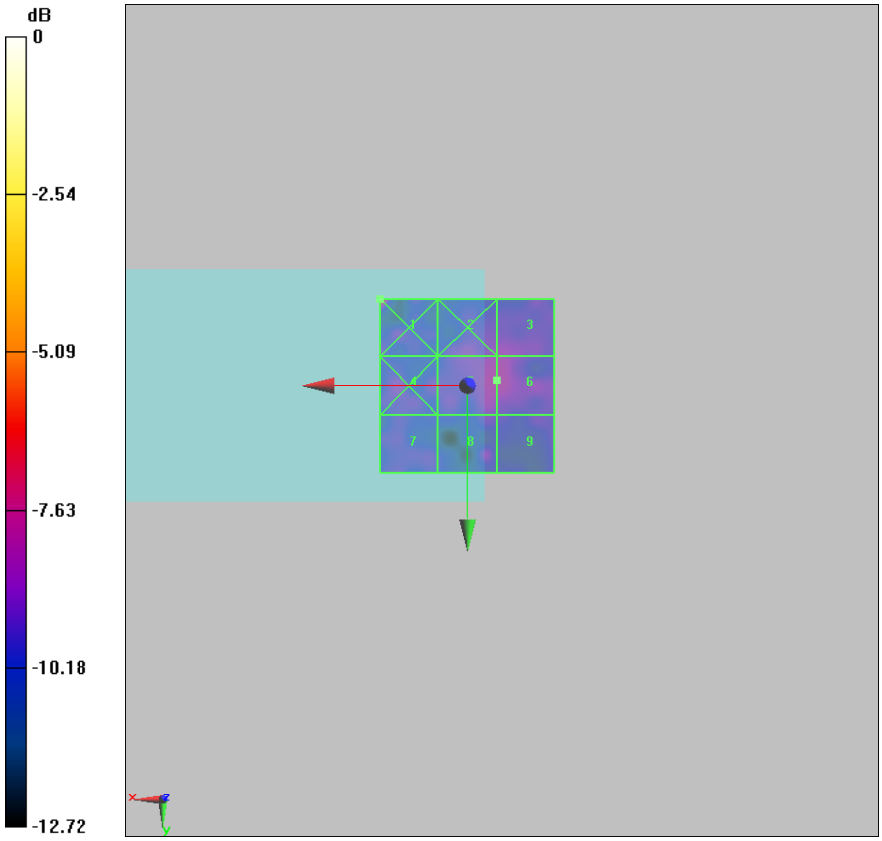
Grid 1 **M4** **24.63 dBV/m**	Grid 2 **M4** **16.08 dBV/m**	Grid 3 **M4** **16.01 dBV/m**
Grid 4 **M4** **16.03 dBV/m**	Grid 5 **M4** **16.42 dBV/m**	Grid 6 **M4** **16.42 dBV/m**
Grid 7 **M4** **15.33 dBV/m**	Grid 8 **M4** **15.63 dBV/m**	Grid 9 **M4** **15.17 dBV/m**

Cursor:

Total = 24.63 dBV/m

E Category: M4

Location: 25, -25, 7.7 mm



0 dB = 17.05 V/m = 24.63 dBV/m

Plot 11 HAC RF E-Field CDMA 1 Middle

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 1880 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC1 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Middle/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 7.048 V/m; Power Drift = -0.17 dB

Applied MIF = 3.26 dB

RF audio interference level = 17.21 dBV/m

Emission category: M4

MIF scaled E-field

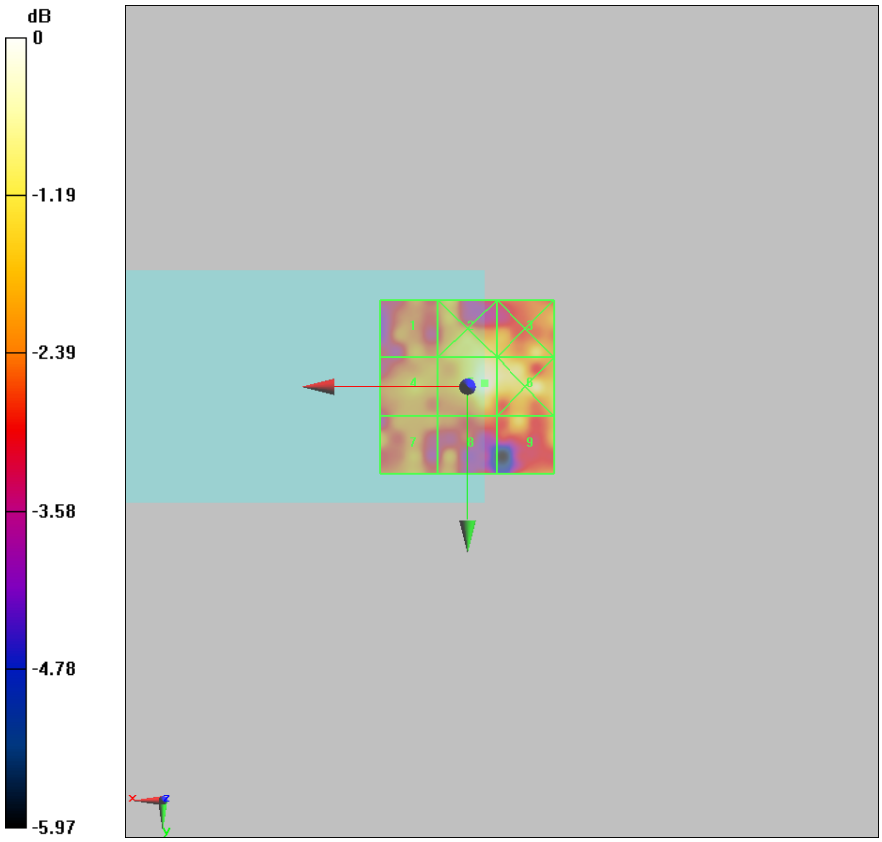
Grid 1 **M4** **15.27 dBV/m**	Grid 2 **M4** **16.38 dBV/m**	Grid 3 **M4** **16.15 dBV/m**
Grid 4 **M4** **15.65 dBV/m**	Grid 5 **M4** **17.21 dBV/m**	Grid 6 **M4** **16.68 dBV/m**
Grid 7 **M4** **15.47 dBV/m**	Grid 8 **M4** **15.24 dBV/m**	Grid 9 **M4** **15.97 dBV/m**

Cursor:

Total = 17.21 dBV/m

E Category: M4

Location: -5, -1, 7.7 mm



0 dB = 7.252 V/m = 17.21 dBV/m

Plot 12 HAC RF E-Field CDMA 1 High

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 1908.75 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC1 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device High/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 6.820 V/m; Power Drift = 0.13 dB

Applied MIF = 3.26 dB

RF audio interference level = 17.13 dBV/m

Emission category: M4

MIF scaled E-field

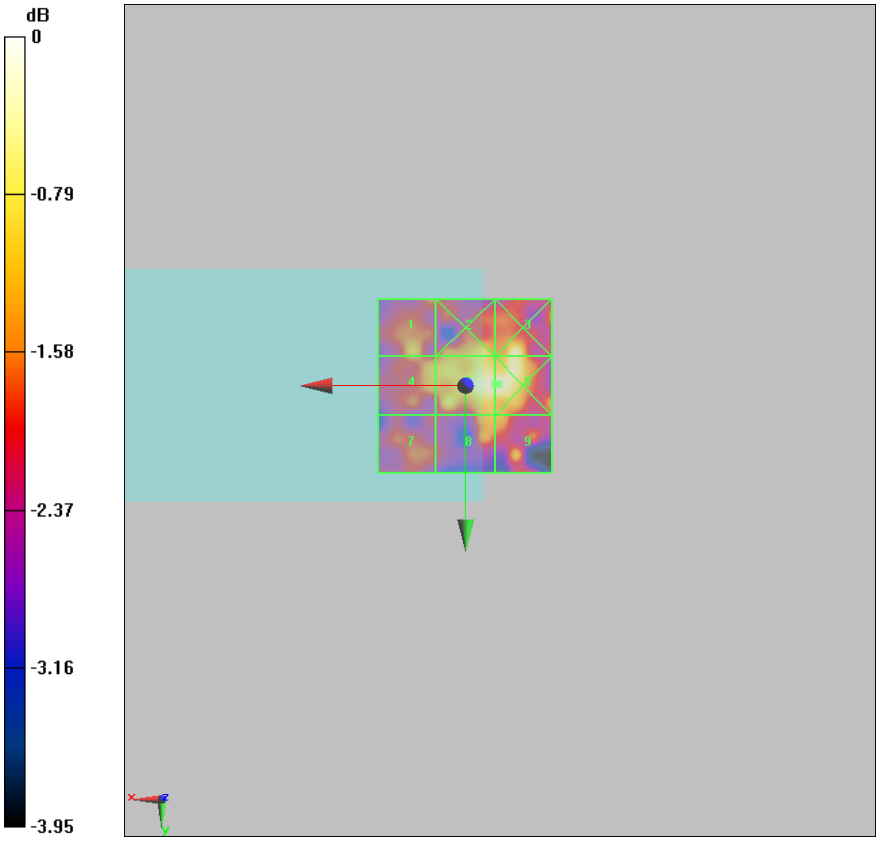
Grid 1 **M4** **16.08 dBV/m**	Grid 2 **M4** **16.42 dBV/m**	Grid 3 **M4** **16.92 dBV/m**
Grid 4 **M4** **16.08 dBV/m**	Grid 5 **M4** **17.13 dBV/m**	Grid 6 **M4** **17.18 dBV/m**
Grid 7 **M4** **15.46 dBV/m**	Grid 8 **M4** **16.13 dBV/m**	Grid 9 **M4** **16.11 dBV/m**

Cursor:

Total = 17.18 dBV/m

E Category: M4

Location: -9.5, -0.5, 7.7 mm



0 dB = 7.224 V/m = 17.18 dBV/m

Plot 13 HAC RF E-Field CDMA 10 Low

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 817.25 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC10 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Low/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 52.02 V/m; Power Drift = 0.07 dB

Applied MIF = 3.26 dB

RF audio interference level = 35.13 dBV/m

Emission category: M4

MIF scaled E-field

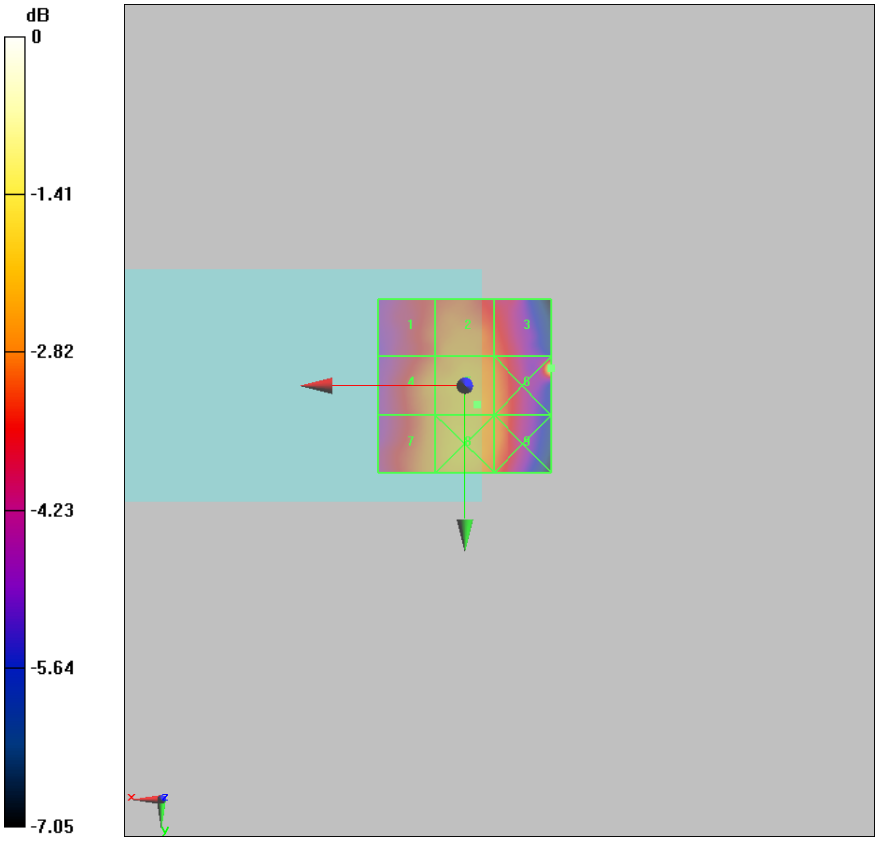
Grid 1 **M4** **34.22 dBV/m**	Grid 2 **M4** **34.71 dBV/m**	Grid 3 **M4** **34.26 dBV/m**
Grid 4 **M4** **34.75 dBV/m**	Grid 5 **M4** **35.13 dBV/m**	Grid 6 **M4** **37.27 dBV/m**
Grid 7 **M4** **34.77 dBV/m**	Grid 8 **M4** **35.26 dBV/m**	Grid 9 **M4** **34.74 dBV/m**

Cursor:

Total = 37.27 dBV/m

E Category: M4

Location: -25, -5, 7.7 mm



0 dB = 73.03 V/m = 37.27 dBV/m

Plot 14 HAC RF E-Field CDMA 10 Middle

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 820 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC10 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device Middle/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 52.41 V/m; Power Drift = -0.06 dB

Applied MIF = 3.26 dB

RF audio interference level = 37.83 dBV/m

Emission category: M4

MIF scaled E-field

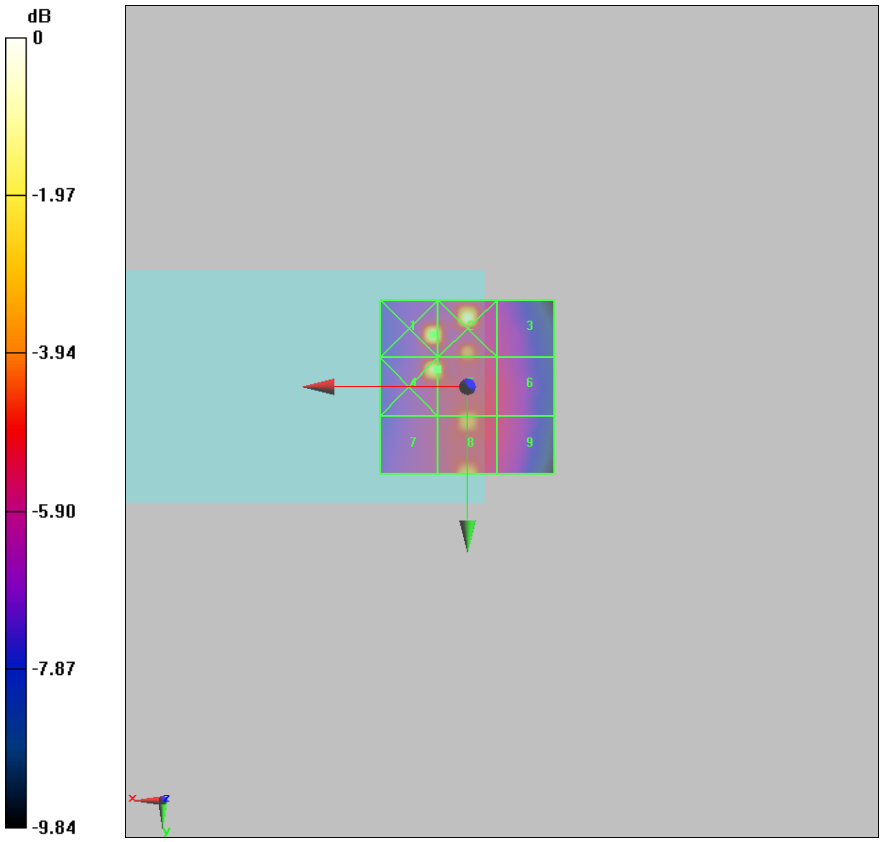
Grid 1 **M3** **40.18 dBV/m**	Grid 2 **M4** **39.83 dBV/m**	Grid 3 **M4** **34.23 dBV/m**
Grid 4 **M4** **38.84 dBV/m**	Grid 5 **M4** **37.83 dBV/m**	Grid 6 **M4** **34.67 dBV/m**
Grid 7 **M4** **34.66 dBV/m**	Grid 8 **M4** **37.53 dBV/m**	Grid 9 **M4** **34.67 dBV/m**

Cursor:

Total = 40.18 dBV/m

E Category: M3

Location: 10, -15, 7.7 mm



0 dB = 102.1 V/m = 40.18 dBV/m

Plot 15 HAC RF E-Field CDMA 10 High

Date: 8/30/2018

Communication System: UID 10295 - AAB, CDMA2000, RC1, SO3, 1/8th Rate 25 fr.; Frequency: 822.75 MHz;Duty Cycle: 1:17.7419

Phantom section: RF Section

DASY5 Configuration:

Sensor-Surface: 0mm (Fix Surface)

Probe: EF3DV3 – SN4048; ConvF(1, 1, 1); Calibrated: 1/8/2018

Electronics: DAE4 SN1317; Calibrated: 3/23/2018

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;

Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7331)

CDMA BC10 HAC RF E-Field 2011 Device E-Field measurement /E Scan - ER3D: 15 mm from Probe Center to the Device High/Hearing Aid Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 50.92 V/m; Power Drift = 0.07 dB

Applied MIF = 3.26 dB

RF audio interference level = 37.29 dBV/m

Emission category: M4

MIF scaled E-field

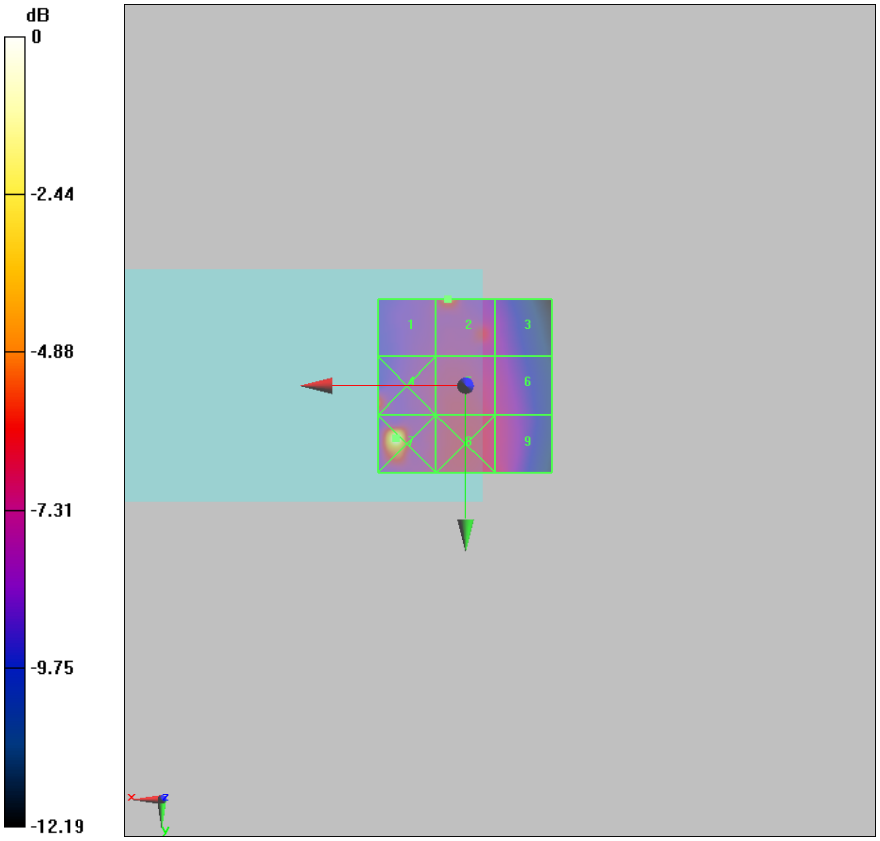
Grid 1 **M4** **34.64 dBV/m**	Grid 2 **M4** **37.29 dBV/m**	Grid 3 **M4** **33.81 dBV/m**
Grid 4 **M4** **36.51 dBV/m**	Grid 5 **M4** **35.22 dBV/m**	Grid 6 **M4** **34.57 dBV/m**
Grid 7 **M3** **41.8 dBV/m**	Grid 8 **M4** **35.34 dBV/m**	Grid 9 **M4** **34.94 dBV/m**

Cursor:

Total = 41.80 dBV/m

E Category: M3

Location: 20, 15, 7.7 mm



0 dB = 123.1 V/m = 41.81 dBV/m